

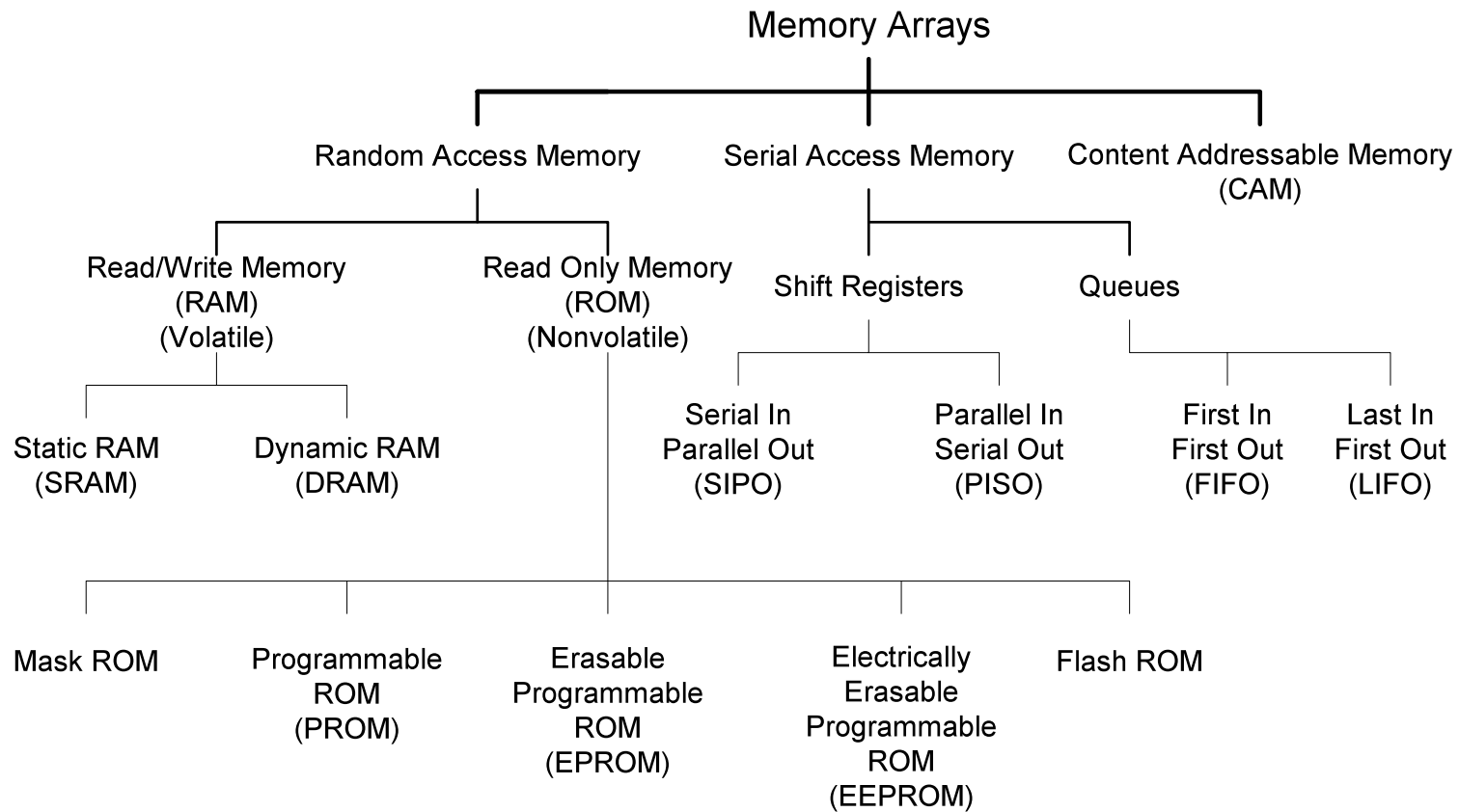
# Lecture 19: SRAM

# Outline

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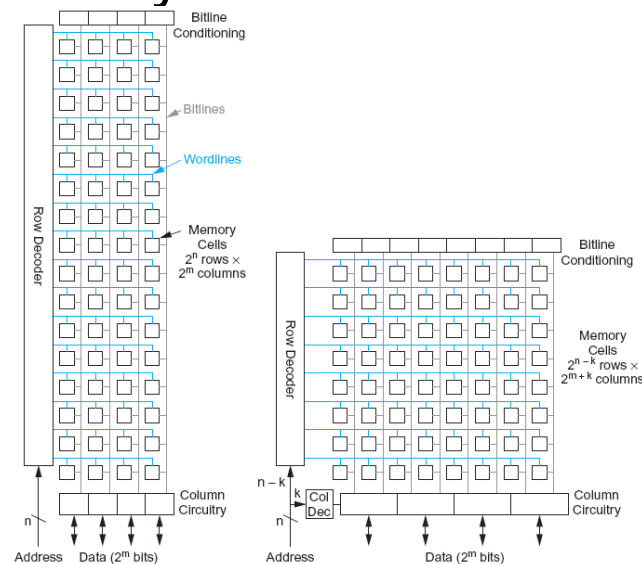
- ❑ Memory Arrays
- ❑ SRAM Architecture
  - SRAM Cell
  - Decoders
  - Column Circuitry

# Memory Arrays



# Array Architecture

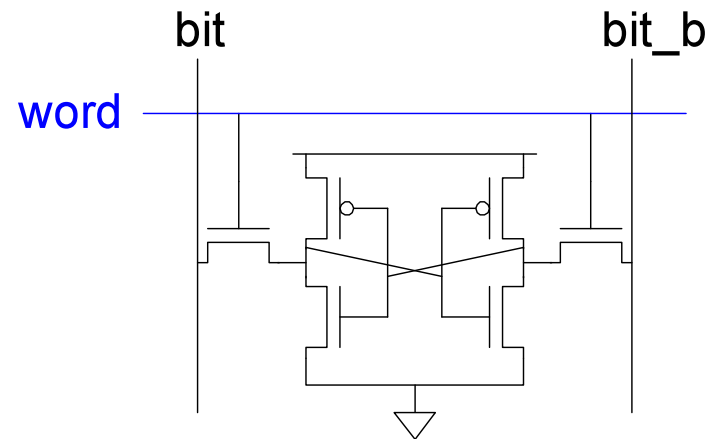
- ❑  $2^n$  words of  $2^m$  bits each
- ❑ If  $n \gg m$ , fold by  $2^k$  into fewer rows of more columns



- ❑ Good regularity – easy to design
- ❑ Very high density if good cells are used

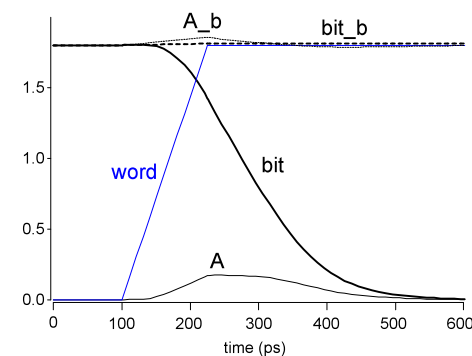
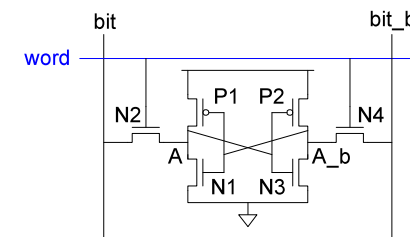
# 6T SRAM Cell

- ❑ Cell size accounts for most of array size
  - Reduce cell size at expense of complexity
- ❑ 6T SRAM Cell
  - Used in most commercial chips
  - Data stored in cross-coupled inverters
- ❑ Read:
  - Precharge bit, bit\_b
  - Raise wordline
- ❑ Write:
  - Drive data onto bit, bit\_b
  - Raise wordline



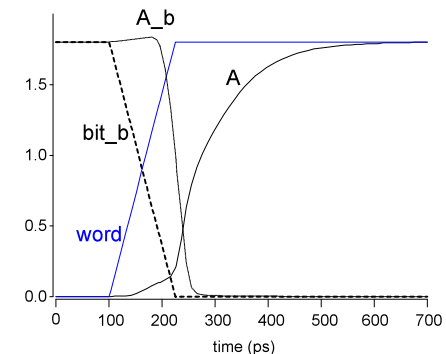
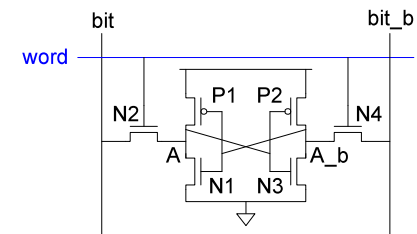
# SRAM Read

- ❑ Precharge both bitlines high
- ❑ Then turn on wordline
- ❑ One of the two bitlines will be pulled down by the cell
- ❑ Ex:  $A = 0$ ,  $A_b = 1$ 
  - bit discharges, bit\_b stays high
  - But A bumps up slightly
- ❑ *Read stability*
  - A must not flip
  - $N1 \gg N2$



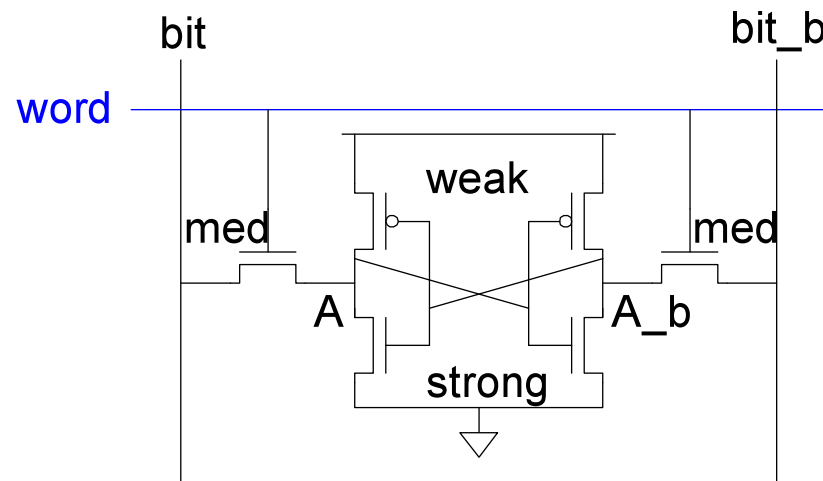
# SRAM Write

- ❑ Drive one bitline high, the other low
- ❑ Then turn on wordline
- ❑ Bitlines overpower cell with new value
- ❑ Ex:  $A = 0$ ,  $A_b = 1$ ,  $\text{bit} = 1$ ,  $\text{bit}_b = 0$ 
  - Force  $A_b$  low, then  $A$  rises high
- ❑ *Writability*
  - Must overpower feedback inverter
  - $N2 \gg P1$



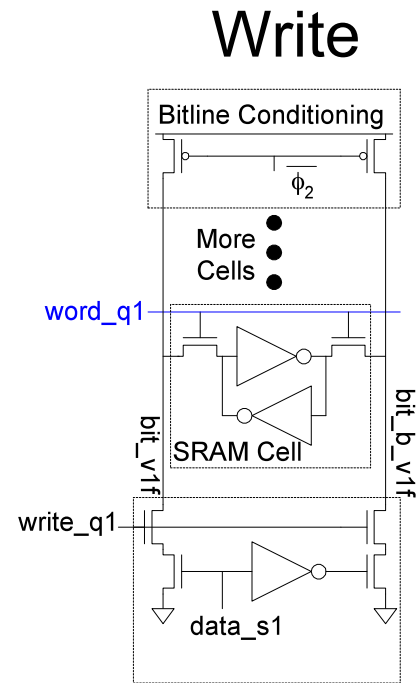
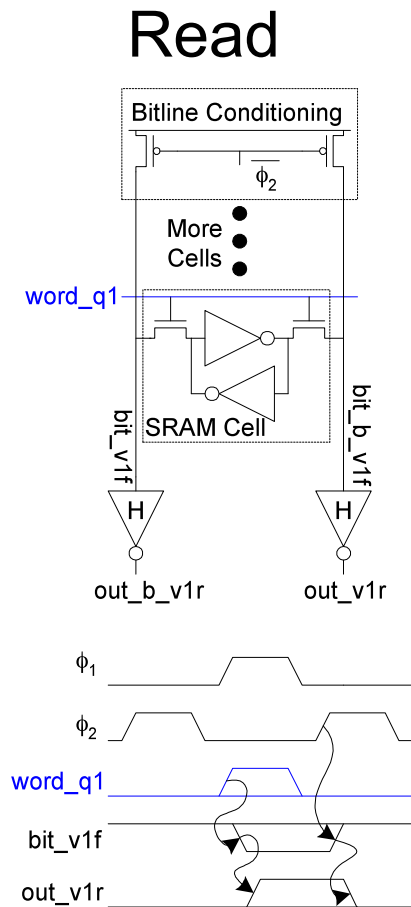
# SRAM Sizing

- ❑ High bitlines must not overpower inverters during reads
- ❑ But low bitlines must write new value into cell



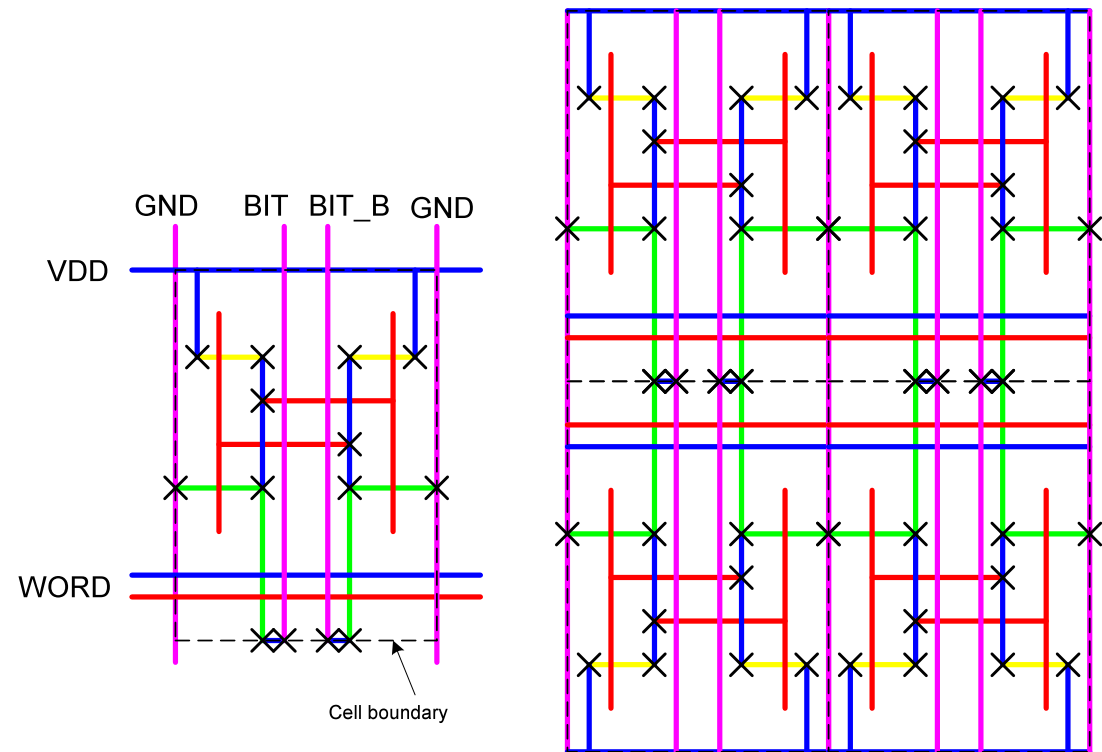
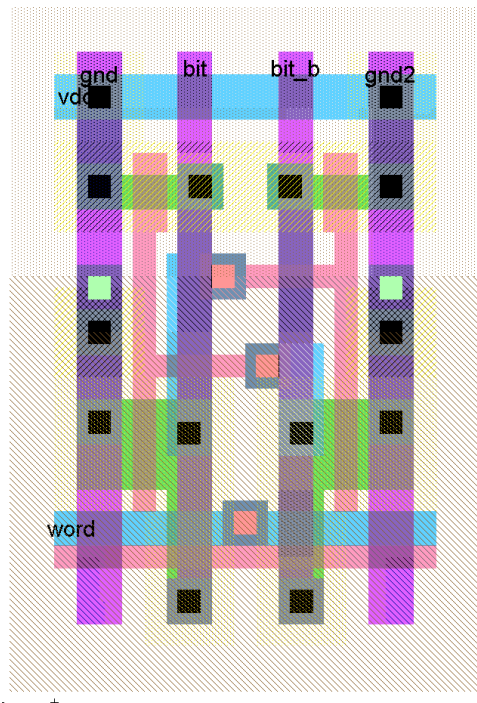


# SRAM Column Example



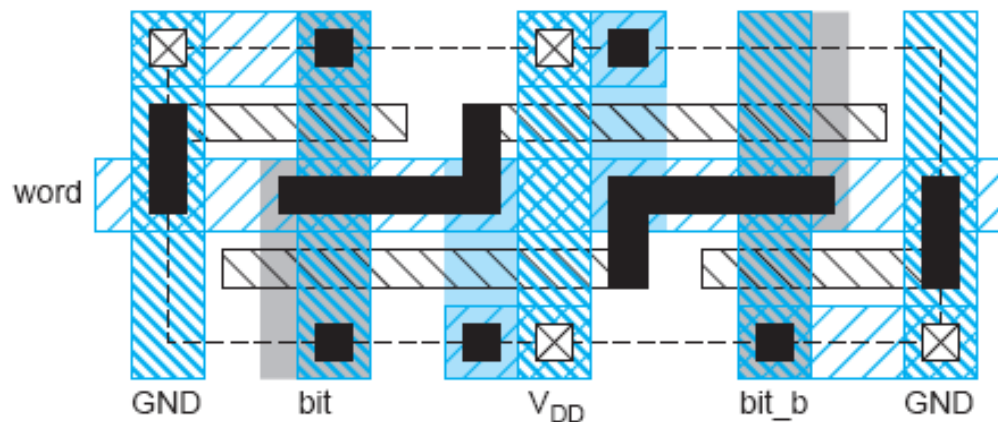
# SRAM Layout

- ❑ Cell size is critical:  $26 \times 45 \lambda$  (even smaller in industry)
- ❑ Tile cells sharing  $V_{DD}$ , GND, bitline contacts



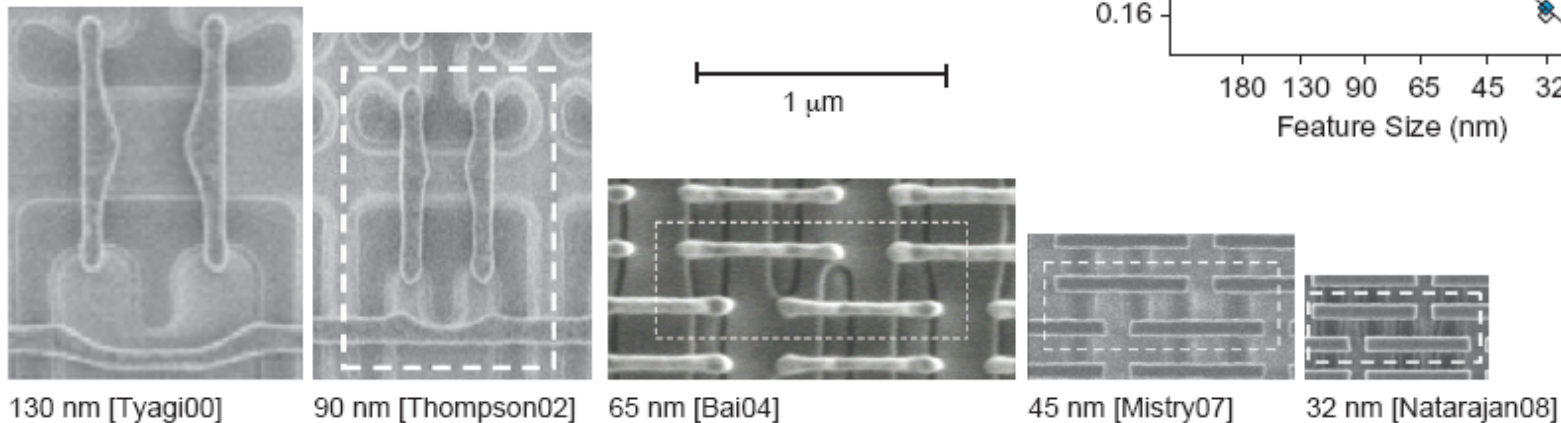
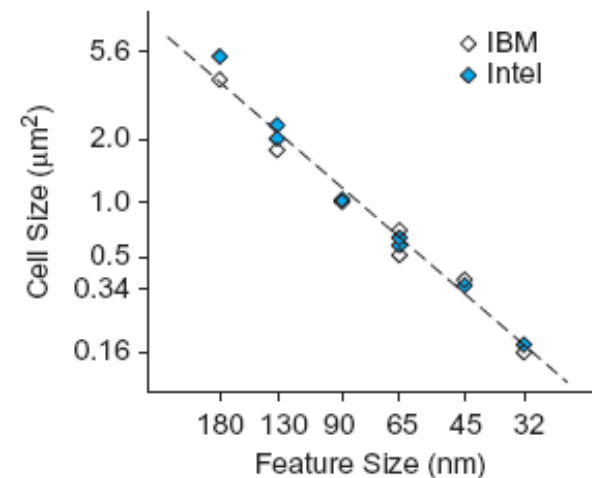
# Thin Cell

- ❑ In nanometer CMOS
  - Avoid bends in polysilicon and diffusion
  - Orient all transistors in one direction
- ❑ *Lithographically friendly* or *thin cell* layout fixes this
  - Also reduces length and capacitance of bitlines



# Commercial SRAMs

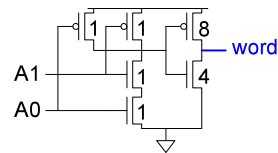
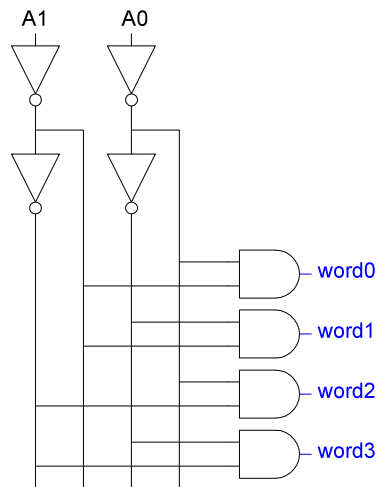
- Five generations of Intel SRAM cell micrographs
  - Transition to thin cell at 65 nm
  - Steady scaling of cell area



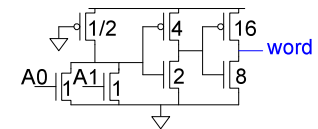
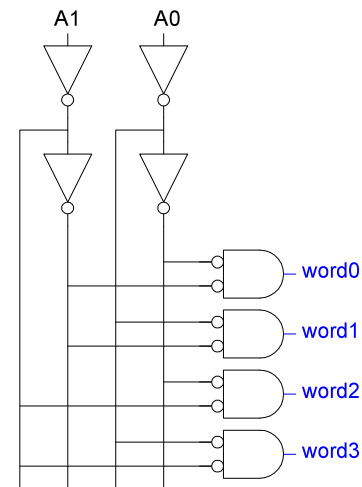
# Decoders

- $n:2^n$  decoder consists of  $2^n$   $n$ -input AND gates
  - One needed for each row of memory
  - Build AND from NAND or NOR gates

## Static CMOS

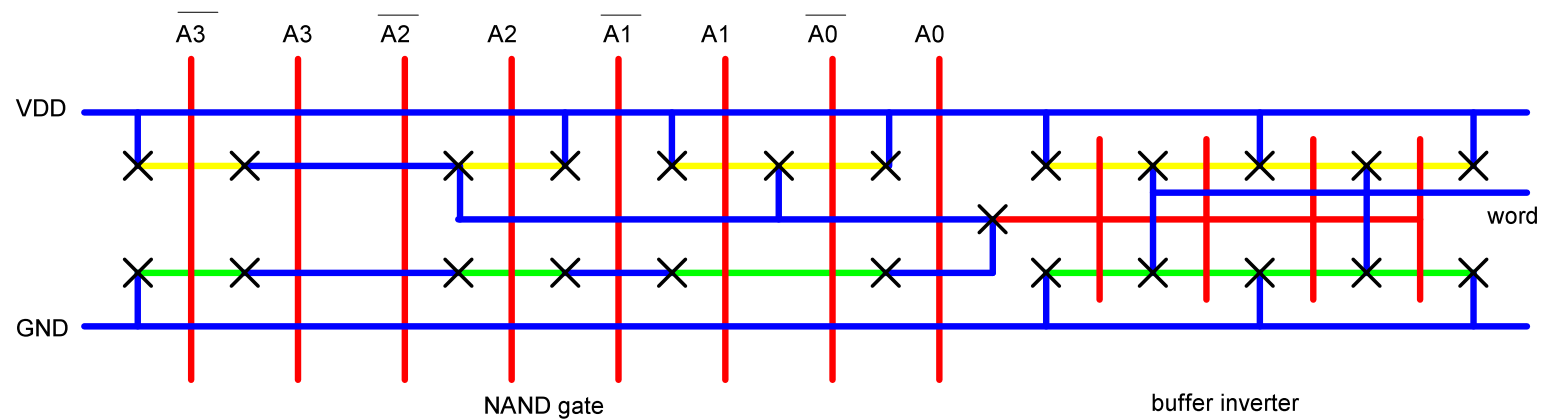


## Pseudo-nMOS



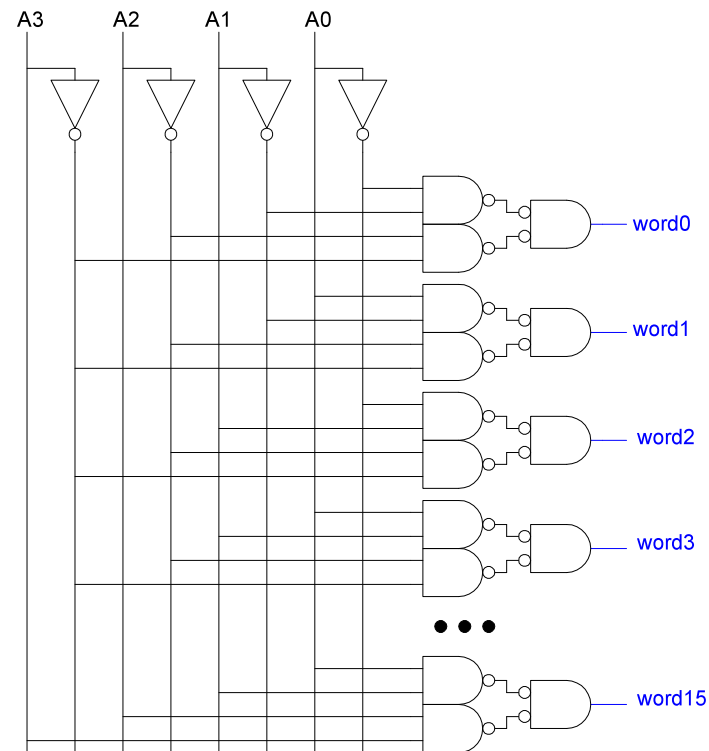
# Decoder Layout

- ❑ Decoders must be pitch-matched to SRAM cell
  - Requires very skinny gates



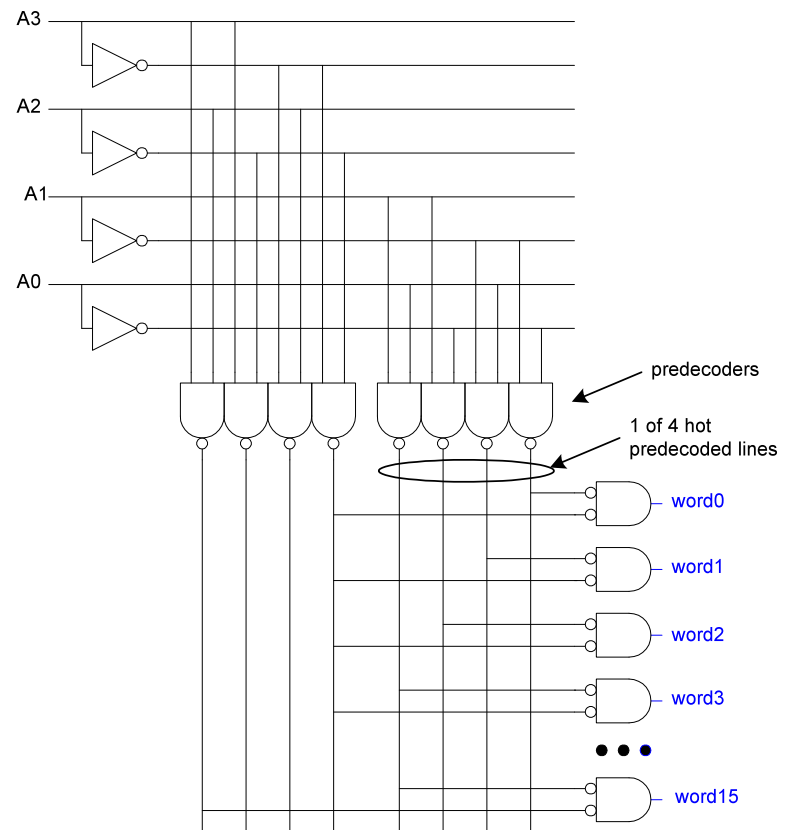
# Large Decoders

- ❑ For  $n > 4$ , NAND gates become slow
  - Break large gates into multiple smaller gates



# Predecoding

- Many of these gates are redundant
  - Factor out common gates into predecoder
  - Saves area
  - Same path effort





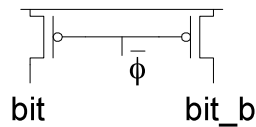
# Column Circuitry

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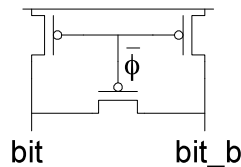
- ❑ Some circuitry is required for each column
  - Bitline conditioning
  - Sense amplifiers
  - Column multiplexing

# Bitline Conditioning

- ❑ Precharge bitlines high before reads



- ❑ Equalize bitlines to minimize voltage difference when using sense amplifiers

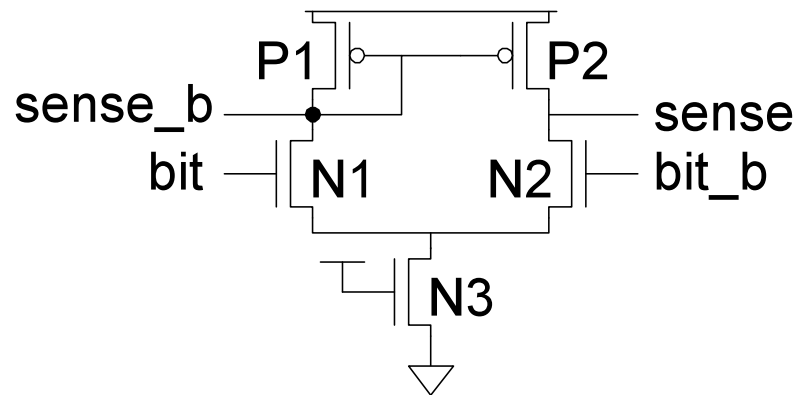


# Sense Amplifiers

- ❑ Bitlines have many cells attached
  - Ex: 32-kbit SRAM has 128 rows x 256 cols
  - 128 cells on each bitline
- ❑  $t_{pd} \propto (C/I) \Delta V$ 
  - Even with shared diffusion contacts, 64C of diffusion capacitance (big C)
  - Discharged slowly through small transistors (small I)
- ❑ *Sense amplifiers* are triggered on small voltage swing (reduce  $\Delta V$ )

# Differential Pair Amp

- ❑ Differential pair requires no clock
- ❑ But always dissipates static power



# Clocked Sense Amp

- ❑ Clocked sense amp saves power
- ❑ Requires sense\_clk after enough bitline swing
- ❑ Isolation transistors cut off large bitline capacitance

